Megger 1700 Series MFT Warning Codes

Test	Warning	Definition
Startup warnings	CAL CHS	Calibration data checksum error
	DAC CHS	Dac data checksum error
	rot CHS	Rotary switch data checksum error
	UNC	Instrument is uncalibrated
Battery	bAt	Low battery
Battery charger	bAt CHA	Battery charging
	bAt FUL	Battery fully charged
Fuse warning	FUS	Fuse blown
Rotary switch setting	ERR ---	General error – invalid combination of rotary switches
Invalid rcd test setting	ERR >1000mA	Requested current is >1000mA
	ERR --- + Type A breaker symbol	Instrument has been previously set for Type A test, but Type A test is not valid with this setting
	ERR --- + Type B breaker symbol	Instrument has been previously set for Type B test, but Type B test is not valid with this setting
	ERR --- + Type S breaker symbol	Instrument has been previously set for Type S test, but Type S test is not valid with this setting
	ERR HI mA	On VAR range, current is set too high for the selected test
Ohms test	VOL 0-L	Voltage overload during test
Insulation test	1000V 1000V	Flashing warning before 1kV test
	VOL 0-L	Voltage overload during test
Earth test	Err REv	During a 2-clamp test, one clamp is the wrong way round
	Err + V clamp symbol	During a 2-clamp test, the V clamp has been opened
	Err + I clamp symbol	During an ART test, the I clamp is the wrong way round
	Err + Rp symbol	Rp resistance is too high
	Err + Rc symbol	Rc resistance is too high
Rcd Test	trp	Supply tripped unexpectedly
	>50V (for example)	Test aborted due to danger of exceeding touch-voltage limit
	Err con	Hardware problem detected during High Current Loop test or RCD test."RE HI" Resistance too high during Type B test
Loop Test	trp	Supply tripped unexpectedly
	>50V (for example)	Test aborted due to danger of exceeding touch-voltage limit
	Err con	Hardware problem detected during High Current Loop test or RCD test
Test will not start	CON	Wrong connection to instrument
	hot	Internal resistors are too hot
	Hot	Internal heatsink is too hot
	VOL >280V (for example)	Supply voltage is too high
	L-N <48V (for example)	Voltage on terminals is too low for L-N loop test
	L-E <48V (for example)	Voltage on terminals is too low for L-E loop test or rcd test
	FRE <45	Supply frequency is too low for loop test or rcd test
	FRE >65	Supply frequency is too high for loop test or rcd test
	NO REF	Loop R1+R2 test attempted without having previously done a Zref test
Test starts but aborts or fails	trp	Supply tripped unexpectedly during loop or rcd test
	>50V (for example)	Rcd or loop test aborted due to danger of exceeding touch-voltage limit
	>280V >10Ω	High Current Loop test measured more than 10 ohms while supply is more than 280V
	RLn >10Ω"	During 3-wire L-E loop test, the line-neutral resistance measured more than 10Ω
	Rn >10Ω"	During 3-wire loop test, the neutral resistance measured more than 10Ω
	Err con	Hardware problem detected during High Current Loop test or RCD test."RE HI" Resistance too high during Type B test
Storage	str o + "k" symbol.	Result stored ok
	FUL	Storage memory is full
Bluetooth	noc Err	Failed to establish connection
	noP Err	Instrument not paired